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| Form PTO-1449 U.S. DEPARTMENT OF COMMERCE (REV. 7-80) PATENT AND TRADEMARK OFFICE | | | | | | | | | | DOCKET NO. | Serial No. |
| | | | | | | | | | | N1 000770 | 09/04/0817 MO 8/17/94 |
| | | | | | | | | | | Applicant Rene Monshouwer et al | |
| Filing Date Concurrently | | Group 2877 PO 8/17/01 | | | | | | | | | |
| INFORMATION DISCLOSURE CITATION (Use several sheets if necessary) | | | | | | | | | | J1017/940819 S.P.O. 08/28/01 | |

U.S. PATENT DOCUMENTS

| Ex. Int. | | Document Number | | | | | | | Date | Name | | Class | Sub-class | Filing Date If Approp. |
|----------|----|-----------------|---|---|---|---|---|---|----------|-----------------|--|-------|-----------|------------------------|
| 120 | AA | 5 | 1 | 4 | 4 | 3 | 6 | 3 | 9/1/92 | Wittekoek et al | | 355 | 53 | 1/24/91 |
| 120 | AB | 4 | 5 | 4 | 0 | 2 | 7 | 7 | 9/10/85 | Mayer et al | | 355 | 53 | 6/24/83 |
| 120 | AC | 4 | 7 | 3 | 7 | 8 | 2 | 3 | 4/12/88 | Bouwer et al | | 355 | 53 | 10/14/86 |
| 120 | AD | 5 | 0 | 2 | 6 | 1 | 6 | 6 | 6/25/91 | Van der Werf | | 356 | 401 | 10/1/84 |
| 120 | AE | 5 | 1 | 9 | 1 | 2 | 0 | 0 | 3/2/93 | Van der Werf | | 250 | 201 | 12/16/91 |
| 120 | AF | 4 | 3 | 5 | 6 | 3 | 9 | 2 | 10/26/82 | Wittekoek et al | | 250 | 201 | 6/11/80 |
| 120 | AG | 4 | 8 | 6 | 1 | 1 | 6 | 2 | 8/29/89 | Ina et al | | 356 | 401 | 11/15/88 |
| 120 | AH | 5 | 4 | 1 | 4 | 5 | 1 | 4 | 5/9/95 | Smith et al | | 356 | 363 | 6/1/93 |
| 120 | AI | 4 | 7 | 7 | 8 | 2 | 7 | 5 | 10/18/88 | Van den Brink | | 356 | 401 | 9/24/86 |
| 120 | AJ | 4 | 2 | 5 | 1 | 1 | 6 | 0 | 2/17/81 | Bouwhuis et al | | 356 | 401 | 7/13/78 |
| 120 | AK | 5 | 2 | 4 | 3 | 1 | 9 | 5 | 9/7/93 | Nishi | | 250 | 548 | 12/29/92 |

FOREIGN PATENT DOCUMENTS

| | | Document Number | | | | | | | Date | Country | | Class | Sub-Class | Trans. | | |
|-----|----|-----------------|---|---|---|---|---|---|------|---------|---------|--------|-----------|--------|----|--|
| | | | | | | | | | | | | | | Yes | No | |
| 120 | AL | 0 | 4 | 9 | 8 | 4 | 9 | 9 | A | 1 | 8/12/92 | Europe | | | X | |
| 120 | AM | 9 | 8 | 3 | 9 | 6 | 8 | 9 | A | 1 | 9/11/98 | World | | | X | |

OTHER (Including Author, Title, Date, Pertinent Pages, Etc.)

| | | | | |
|----------|---------------------|---|-----------------|---------|
| 120 | AN | "Submicrometer Lithographic Alignment and Overlay Strategies", by Saleem H. Zaidi et al, SPIE Vol. 1343, 1990, pages 245-255. | | |
| 120 | AO | "Submicron 1:1 Optical Lighography", by David A. Markle, Semiconductor International May 1986. | | |
| Examiner | <i>Dave Johnson</i> | | Date Considered | 8/17/94 |